



Transient Data Acquisition
Capture, Calculate, Customize

Dear ,

Hi-Techniques is off to a great start for 2004 - new products, new applications, and new personnel. We are pleased to welcome a new member to our technical sales and support team. Keith Martinko joins us with a strong background in transient data acquisition and analysis.

Please contact him at keithm@hi-techniques.com, or 800-248-1633 if you have any questions regarding your application needs.



Product News - Compact, Portable, meDAQ



You can now access the full acquisition power of the popular Hi-Techniques Win600e data acquisition system in a new, compact frame. Our new meDAQ allows you to design a fully portable and distributed application, with our high speed

transient signal conditioning and digitizing hardware placed close to the transducers. This helps to improve test setup times and reduce noise transmission since signal lines from the sensor to the data acquisition frame can be significantly reduced. A single Ethernet cable connects the meDAQ(s) to a Windows-based PC. Other features include :

- « Small, portable, DC-powered
- « Ideal for fast transient measurements of voltage, current, pressure, strain/bridge and current-fed accelerometers
- « 2 to 16 simultaneously sampled channels from 100 kSps to 50 MSps per frame
- « Remote operation via Ethernet ... link multiple frames to create a distributed DAS with hundreds of channels
- « Dedicated on-board channel memory for transient or streaming applications
- « Sophisticated triggering and auto-start capabilities
- « Includes our easy-to-setup Hi-Techniques software ... intelligently taking you from data capture to report generation!

[Learn more about the meDAQ »](#)

Application - Circuit Breaker Testing

Circuit Breaker Testing involves both general power measurements and specialized measurements for I²T and Asymmetrical current. A suite of programs can help automate these standard tests and speed the reports needed for the CB and power industry. We have recently added the standard 1.2 -50 µsec and 8-50 µsec lightning tests for surge protectors to our suite of power programs. A package including the following is available for your review:

- « Calibration (for scaling current and voltage waveforms)
- « Power (for continuous sinusoids - inc. RMS, Apparent, Average, Power Factor)
- « Power Factor (OC tests)
- « Asymmetrical Current (OC tests)
- « I²T (Half-sine pulse)
- « Lightning Tests - 1.2 /50 and 8/20 µsec tests

The Hi-Techniques products offer a unique blend of pre-programmed algorithms and user-defined programs. It is easy to alter the programs to fit special needs or make further calculations required by your special circumstances.

How To - Files & Folders

How can you control user-selected disk paths from programs? From your Win600 program, ask an operator to find a setup (or any) file:

SET = DSK *.SET (asterisk stands for "any") or
 TR1 = DSK *.DAT (user selects a data file for Trace 1)

Now save the path selected by the user:
 SAVE PATH IN STR1

To recall it, making it the default path:
 DSK PATH = {S1}
 The squiggly brackets embed strings and numeric registers in the files and paths

[Find out more about this »](#)

What, Where, and When

Shows: [SAE World Congress](#) - March 8 - 11, 2004 - Booth # 833
[DATA](#) - Orlando, FL - March 16, 2004
[DATA](#) - Clearwater, FL - March 18, 2004
[DATA](#) - Cleveland, OH - May 18, 2004
[DATA](#) - Detroit, MI - May 20, 2004
[Sensors](#) - Detroit - June 7 - 10, 2004

Training: In-house [May 17-21](#)

Updates: [Win600e 5.00.16](#) with Shock Response Spectrum and Strain Gauge calibration
 If you need password information please contact us at info@hi-techniques.com or 800-248-1633.